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Application/Control No.	Applicant(s)/Patent under Reexamination
10/802,735	TAKAFUJI ET AL.
Examiner	Art Unit
Thien F. Tran	2811

Thien F. Tran

SEARCHED				
Class	Subclass	Date	Examiner	
257	59, 64 66, 69 70, 72 347	9/8/2005	π	
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Search history printout	2/13/2006	π